

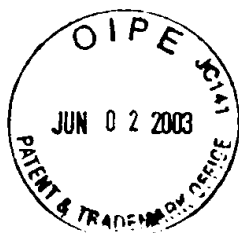
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Hisaya MORI, et al.

Serial No.: 09/927,368

Filed: August 13, 2001



Group Art Unit: 2829

Examiner Chan, Emily T.

For: APPARATUS AND METHOD FOR TESTING SEMICONDUCTOR INTEGRATED CIRCUIT

Mail Stop Non Fee Amendment

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Dear Sir:

Transmitted herewith is an Amendment in the above-identified application.

- ☐ No additional fee is required.
☐ Applicant is entitled to small entity status under 37 CFR 1.27
☐ Also attached:

The fee has been calculated as shown below:

| | NO. OF CLAIMS | HIGHEST PREVIOUSLY PAID FOR | EXTRA CLAIMS | RATE | FEE |
|---------------------------------|---------------|-----------------------------|--------------|-----------|--------|
| Total Claims | 11 | 20 | 0 | \$18.00 = | \$0.00 |
| Independent Claims | 2 | 3 | 0 | \$84.00 = | \$0.00 |
| Multiple claims newly presented | | | | | \$0.00 |
| Fee for extension of time | | | | | \$0.00 |
| Total of Above Calculations | | | | | \$0.00 |

- ☐ Please charge my Deposit Account No. 500417 in the amount of \$0.00. An additional copy of this transmittal sheet is submitted herewith.
- ☒ The Commissioner is hereby authorized to charge payment of any fees associated with this communication or credit any overpayment, to Deposit Account No. 500417, including any filing fees under 37 CFR 1.16 for presentation of extra claims and any patent application processing fees under 37 CFR 1.17.

Respectfully submitted,

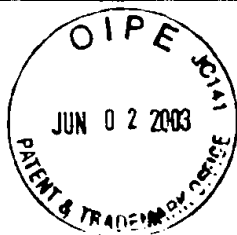
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Date: June 2, 2003

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Docket No.: 50090-332



PATENT

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INTEGRATED CIRCUIT

AMENDMENT

Commissioner for Patents
Washington, DC 20231

Sir:

In response to the Office Action mailed March 14, 2003, please amend the above-identified application as follows:

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TECHNICAL
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